

Die Datasheet

GA10JT12-CAL

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1200 V

100 mΩ

25 A

80

Normally – OFF Silicon Carbide Junction Transistor

Features

- 210 °C Maximum Operating Temperature
- Gate Oxide Free SiC Switch
- Exceptional Safe Operating Area
- Excellent Gain Linearity
- Temperature Independent Switching Performance
- Low Output Capacitance
- Positive Temperature Coefficient of R_{DS,ON}
- Suitable for Connecting an Anti-parallel Diode

Advantages

- Compatible with Si MOSFET/IGBT Gate Drive ICs
- > 20 µs Short-Circuit Withstand Capability
- Lowest-in-class Conduction Losses
- High Circuit Efficiency
- Minimal Input Signal Distortion
- High Amplifier Bandwidth





Die Size = 2.10 mm x 2.10 mm

Applications

• Down Hole Oil Drilling, Geothermal Instrumentation

 V_{DS}

 \mathbf{h}_{FE}

R_{DS(ON)}

I_D @ 25 °C

- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

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Section I: Absolute Maximum Ratings

(T_c = 25 °C unless otherwise specified)

Parameter	Symbol	Conditions	Value	Unit	Notes
Drain – Source Voltage	V _{DS}	$V_{GS} = 0 V$	1200	V	
Continuous Drain Current	Ι _D	$T_{\rm C} = 25^{\circ}{\rm C}$	25	А	
Continuous Drain Current	Ι _D	$T_C > 125$ °C, assumes $R_{thJC} < 0.88$ °C/W	10	А	
Continuous Gate Current	l _G		1.3	А	
Turn-Off Safe Operating Area	RBSOA	$T_{VJ} = 210 \ ^{\circ}C$, Clamped Inductive Load	$I_{D,max} = 10$ @ $V_{DS} \le V_{DSmax}$	А	Fig. 16
Short Circuit Safe Operating Area	SCSOA	T_{VJ} = 210 °C, I_G = 1 A, V_{DS} = 800 V, Non Repetitive	>20	μs	
Reverse Gate – Source Voltage	V _{SG}		30	V	
Reverse Drain – Source Voltage	V _{SD}		25	V	
Operating Junction and Storage Temperature	T_{j},T_{stg}		-55 to 210	°C	
Maximum Processing Temperature	T _{Proc}	10 min. maximum	325	°C	

Section II: Static Electrical Characteristics

Devenueter	Cumulant	Conditions		Value		11	Neter
Parameter	Symbol	Conditions	Min.	Typical	Max.	Unit	Notes
A: On State							
Drain – Source On Resistance	R _{DS(ON)}	$ \begin{array}{l} I_{D} = 10 \text{ A}, \ T_{j} = 25 \ ^{\circ}\text{C} \\ I_{D} = 10 \text{ A}, \ T_{j} = 150 \ ^{\circ}\text{C} \\ I_{D} = 10 \text{ A}, \ T_{j} = 175 \ ^{\circ}\text{C} \end{array} $		100 160 180		mΩ	Fig. 4
Gate – Source Saturation Voltage	$V_{\text{GS,SAT}}$	$ I_D = 10 \text{ A}, \ I_D/I_G = 40, \ T_j = 25 \ ^\circ\text{C} \\ I_D = 10 \text{ A}, \ I_D/I_G = 30, \ T_j = 175 \ ^\circ\text{C} $		3.50 3.27		V	Fig. 7
DC Current Gain	h _{FE}	$ \begin{array}{l} V_{DS} = 8 \ V, \ I_D = 10 \ A, \ T_j = 25 \ ^{\circ}\text{C} \\ V_{DS} = 8 \ V, \ I_D = 10 \ A, \ T_j = 125 \ ^{\circ}\text{C} \\ V_{DS} = 8 \ V, \ I_D = 10 \ A, \ T_j = 175 \ ^{\circ}\text{C} \end{array} $		80 55 50		_	Fig. 5
B: Off State							
Drain Leakage Current	I _{DSS}	$ \begin{array}{l} V_{DS} = 1200 \; V, \; V_{GS} = 0 \; V, \; T_{j} = 25 \; ^{\circ}\text{C} \\ V_{DS} = 1200 \; V, \; V_{GS} = 0 \; V, \; T_{j} = 150 \; ^{\circ}\text{C} \\ V_{DS} = 1200 \; V, \; V_{GS} = 0 \; V, \; T_{j} = 175 \; ^{\circ}\text{C} \end{array} $		1 1 2		μΑ	Fig. 8
Gate Leakage Current	I _{SG}	V _{SG} = 20 V, T _i = 25 °C		20		nA	

Section III: Dynamic Electrical Characteristics

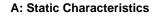
Parameter	Symbol	Conditions		Value		Unit	Notes	
i aranieter Syn		conditions		Min. Typical Max.		Unit	Notes	
A: Capacitance and Gate Charge	9							
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 800 V, <i>f</i> = 1 MHz		1275		pF	Fig. 9	
Reverse Transfer/Output Capacitance	C_{rss}/C_{oss}	V _{DS} = 800 V, <i>f</i> = 1 MHz		30		pF	Fig. 9	
Output Capacitance Stored Energy	Eoss	V _{GS} = 0 V, V _{DS} = 800 V, <i>f</i> = 1 MHz		12		μJ	Fig. 10	
Effective Output Capacitance, time related	$C_{\text{oss,tr}}$	I_{D} = constant, V_{GS} = 0 V, V_{DS} = 0800 V		55		pF		
Effective Output Capacitance, energy related	$C_{\text{oss,er}}$	$V_{GS} = 0 V, V_{DS} = 0800 V$		40		pF		
Gate-Source Charge	Q _{GS}	V _{GS} = -53 V		11		nC		
Gate-Drain Charge	Q_{GD}	V _{GS} = 0 V, V _{DS} = 0800 V		55		nC		
Gate Charge - Total	Q_{G}			66		nC		
B: Switching ¹ Internal Gate Resistance – ON	P	V _{GS} > 2.5 V, V _{DS} = 0 V, T _i = 175 °C		0.19		Ω		
Turn On Delay Time	R _{G(INT-ON)} t _{d(on)}			10		ns		
Fall Time, V _{DS}	t _f	$_T_j = 25 \text{ °C}, V_{DS} = 800 \text{ V},$ $I_D = 10 \text{ A}, \text{ Resistive Load}$		10		ns	Fig. 11, 13	
Turn Off Delay Time	t _{d(off)}	B = 10 A, Resistive Load Refer to Section V for additional		22		ns	1 ig. 1 i, 13	
Rise Time, V _{DS}	tr	driving information.		10		ns	Fig. 12, 14	
Turn On Delay Time	t _{d(on)}			10		ns	119.12,14	
Fall Time, V_{DS}	t _f	T _i = 175 °C, V _{DS} = 800 V,	-	10		ns	Fig. 11	
Turn Off Delay Time	t _{d(off)}	$I_{\rm D} = 10$ A, Resistive Load		35		ns		
Rise Time, V _{DS}	t _r			10		ns	Fig. 12	
Turn-On Energy Per Pulse	Eon	T _i = 25 °C, V _{DS} = 800 V,		140		μJ	Fig. 11, 13	
Turn-Off Energy Per Pulse	Eoff	$I_D = 10 \text{ A}$, Inductive Load		10		μJ	Fig. 12, 14	
Total Switching Energy	E _{tot}	Refer to Section V.		150		μJ	<u> </u>	
Turn-On Energy Per Pulse	Eon			140		μJ	Fig. 11	
Turn-Off Energy Per Pulse	E _{off}	$-T_j = 175 ^{\circ}C, V_{DS} = 800 V,$ $-I_D = 10 A, Inductive Load$		100		μJ	Fig. 12	
Total Switching Energy	E _{tot}	$m_D = 10 \text{ A}$, inductive Load		150		μJ	~	

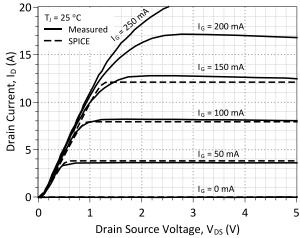
 1 – All times are relative to the Drain-Source Voltage V_{DS}



GA10JT12-CAL

Section IV: Figures







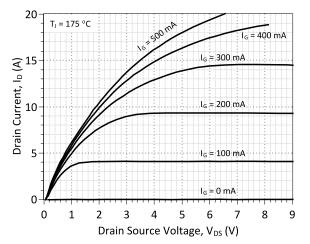


Figure 3: Typical Output Characteristics at 175 °C

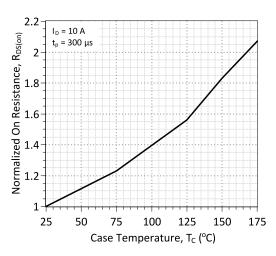


Figure 5: Normalized On-Resistance vs. Temperature

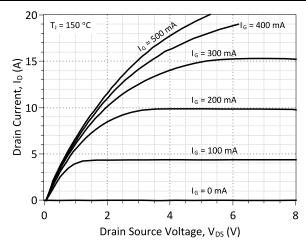


Figure 2: Typical Output Characteristics at 150 °C

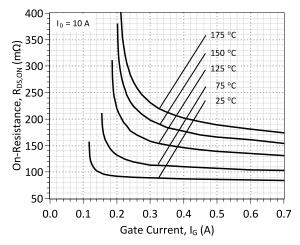
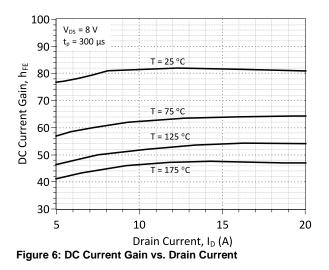


Figure 4: On-Resistance vs. Gate Current



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GA10JT12-CAL

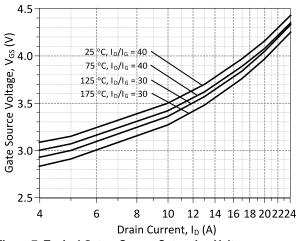


Figure 7: Typical Gate – Source Saturation Voltage



Dυ

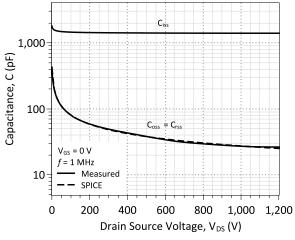


Figure 9: Input, Output, and Reverse Transfer Capacitance

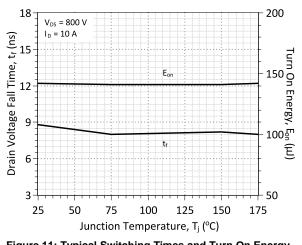


Figure 11: Typical Switching Times and Turn On Energy Losses vs. Temperature

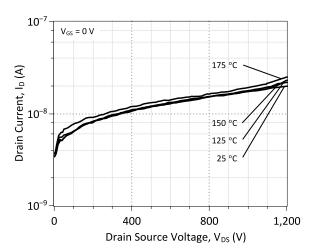


Figure 8: Typical Blocking Characteristics

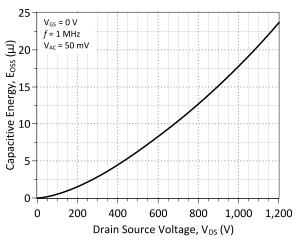


Figure 10: Energy Stored in Output Capacitance

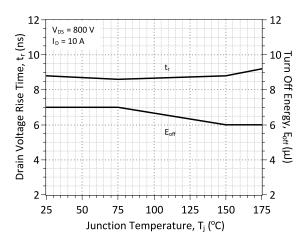


Figure 12: Typical Switching Times and Turn Off Energy Losses vs. Temperature

Die Datasheet

GA10JT12-CAL

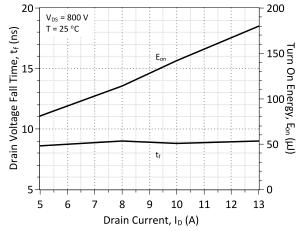


Figure 13: Typical Switching Times and Turn On Energy Losses vs. Drain Current

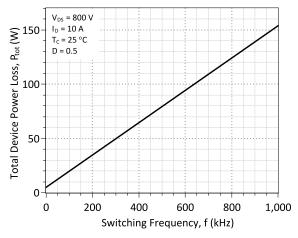


Figure 15: Typical Hard Switched Device Power Loss vs. Switching Frequency²

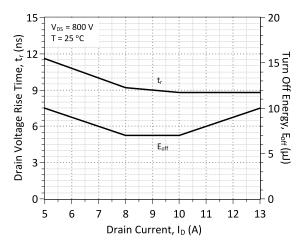


Figure 14: Typical Switching Times and Turn Off Energy Losses vs. Drain Current

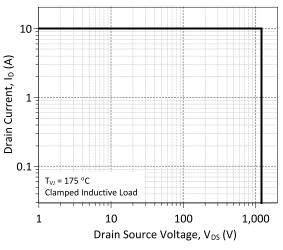


Figure 16: Turn-Off Safe Operating Area

² – Representative values based on device conduction and switching loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.



Section V: Driving the GA10JT12-CAL

Drive Topology	Gate Drive Power Consumption	Switching Frequency	Application Emphasis	Availability
TTL Logic	High	Low	Wide Temperature Range	Coming Soon
Constant Current	Medium	Medium	Wide Temperature Range	Coming Soon
High Speed – Boost Capacitor	Medium	High	Fast Switching	Production
High Speed – Boost Inductor	Low	High	Ultra Fast Switching	Coming Soon
Proportional	Lowest	High	Wide Drain Current Range	Coming Soon
Pulsed Power	Medium	N/A	Pulse Power	Coming Soon

A: Static TTL Logic Driving

The GA10JT12-CAL may be driven using direct (5 V) TTL logic after current amplification. The (amplified) current level of the supply must meet or exceed the steady state gate current ($I_{G,steady}$) required to operate the GA10JT12- CAL. The power level of the supply can be estimated from the target duty cycle of the particular application. $I_{G,steady}$ is dependent on the anticipated drain current ID through the SJT and the DC current gain h_{FE} , it may be calculated from the following equation. An accurate value of the h_{FE} may be read from Figure 6.

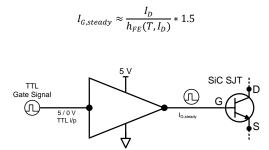


Figure 17: TTL Gate Drive Schematic

B: High Speed Driving

The SJT is a current controlled transistor which requires a positive gate current for turn-on as well as to remain in on-state. An ideal gate current waveform for ultra-fast switching of the SJT, while maintaining low gate drive losses, is shown in Figure 18 which features a positive current peak during turn-on, a negative current peak during turn-off, and continuous gate current to remain on.

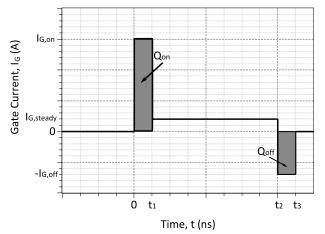


Figure 18: An idealized gate current waveform for fast switching of an SJT.

An SJT is rapidly switched from its blocking state to on-state, when the necessary gate charge, Q_G , for turn-on is supplied by a burst of high gate current, $I_{G,on}$, until the gate-source capacitance, C_{GS} , and gate-drain capacitance, C_{GD} , are fully charged.

$$\begin{aligned} Q_{on} &= I_{G,on} * t_1 \\ Q_{on} &\geq Q_{gs} + Q_{gd} \end{aligned}$$



Ideally, $I_{G,pon}$ should terminate when the drain voltage falls to its on-state value in order to avoid unnecessary drive losses during the steady on-state. In practice, the rise time of the $I_{G,on}$ pulse is affected by the parasitic inductances, L_{par} in the device package and drive circuit. A voltage developed across the parasitic inductance in the source path, L_s , can de-bias the gate-source junction, when high drain currents begin to flow through the device. The voltage applied to the gate pin should be maintained high enough, above the $V_{GS,sat}$ (see**Error! Reference ource not found.**) level to counter these effects.

A high negative peak current, $-I_{G,off}$ is recommended at the start of the turn-off transition, in order to rapidly sweep out the injected carriers from the gate, and achieve rapid turn-off. While satisfactory turn off can be achieved with $V_{GS} = 0$ V, a negative gate voltage V_{GS} may be used in order to speed up the turn-off transition.

Two high-speed drive topologies for the SiC SJTs are presented below.

B:1: High Speed, Low Loss Drive with Boost Capacitor, GA03IDDJT30-FR4

The GA10JT12- CAL may be driven using a High Speed, Low Loss Drive with Boost Capacitor topology in which multiple voltage levels, a gate resistor, and a gate capacitor are used to provide fast switching current peaks at turn-on and turn-off and a continuous gate current while in on-state. A 3 kV isolated evaluation gate drive board (GA03IDDJT30-FR4) utilizing this topology is commercially available for high and low-side driving, its datasheet provides additional details about this drive topology.

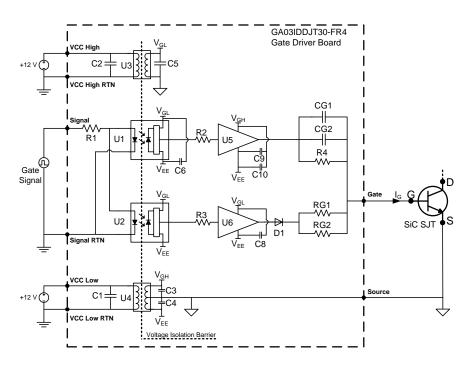


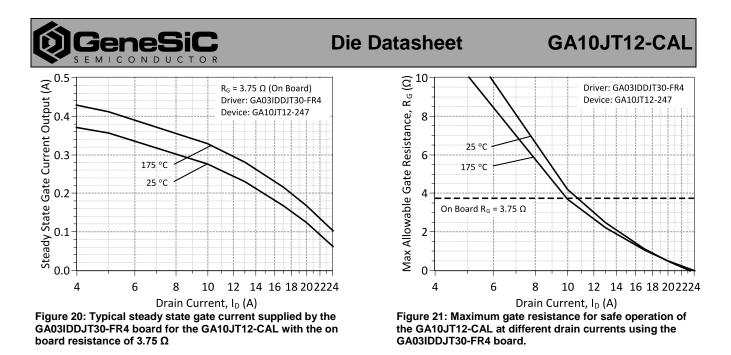
Figure 19: Topology of the GA03IDDJT30-FR4 Two Voltage Source gate driver.

The GA03IDDJT30-FR4 evaluation board comes equipped with two on board gate drive resistors (RG1, RG2) pre-installed for an effective gate resistance³ of $R_G = 3.75 \Omega$. It may be necessary for the user to reduce RG1 and RG2 under high drain current conditions for safe operation of the GA10JT12- CAL. The steady state current supplied to the gate pin of the GA10JT12- CAL with on-board $R_G = 3.75 \Omega$, is shown in Figure 20. The maximum allowable safe value of R_G for the user's required drain current can be read from Figure 21.

For the GA10JT12-CAL, R_g must be reduced for $I_D \ge \sim 10$ A for safe operation with the GA03IDDJT30-FR4.

For operation at $I_D \ge \sim 10$ A, R_G may be calculated from the following equation, which contains the DC current gain h_{FE} (Figure 6) and the gate-source saturation voltage $V_{GS,sat}$ (Figure 7).

$$R_{G,max} = \frac{\left(4.7V - V_{GS,sat}\right) * h_{FE}(T, I_D)}{I_D * 1.5} - 0.6\Omega$$



B:2: High Speed, Low Loss Drive with Boost Inductor

A High Speed, Low-Loss Driver with Boost Inductor is also capable of driving the GA10JT12- CAL at high-speed. It utilizes a gate drive inductor instead of a capacitor to provide the high-current gate current pulses $I_{G,on}$ and $I_{G,off}$. During operation, inductor L is charged to a specified $I_{G,on}$ current value then made to discharge I_L into the SJT gate pin using logic control of S₁, S₂, S₃, and S₄, as shown in Figure 22. After turn on, while the device remains on the necessary steady state gate current $I_{G,steady}$ is supplied from source VCC through RG. Please refer to the article "A current-source concept for fast and efficient driving of silicon carbide transistors" by Dr. Jacek Rąbkowski for additional information on this driving topology.⁴

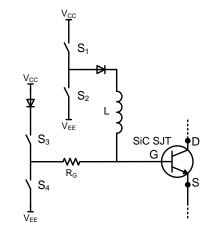


Figure 22: Simplified Inductive Pulsed Drive Topology

⁴ – Archives of Electrical Engineering. Volume 62, Issue 2, Pages 333–343, ISSN (Print) 0004-0746, DOI: 10.2478/aee-2013-0026, June 2013

 $^{^{3}}$ - R_G = (1/RG1 +1/RG2)⁻¹. Driver is pre-installed with RG1 = RG2 = 7.5 Ω



C: Proportional Gate Current Driving

For applications in which the GA10JT12- CAL will operate over a wide range of drain current conditions, it may be beneficial to drive the device using a proportional gate drive topology to optimize gate drive power consumption. A proportional gate driver relies on instantaneous drain current I_D feedback to vary the steady state gate current $I_{G,steady}$ supplied to the GA10JT12- CAL

C:1: Voltage Controlled Proportional Driver

The voltage controlled proportional driver relies on a gate drive IC to detect the GA10JT12- CAL drain-source voltage V_{DS} during on-state to sense I_D. The gate drive IC will then increase or decrease I_{G,steady} in response to I_D. This allows I_{G,steady}, and thus the gate drive power consumption, to be reduced while I_D is relatively low or for I_{G,steady} to increase when is I_D higher. A high voltage diode connected between the drain and sense protects the IC from high-voltage when the driver and GA10JT12- CAL are in off-state. A simplified version of this topology is shown in Figure 23, additional information will be available in the future at http://www.genesicsemi.com/commercial-sic/sic-junction-transistors/

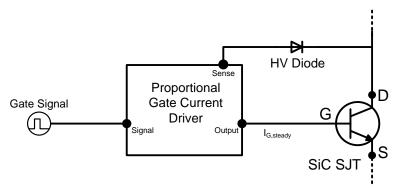


Figure 23: Simplified Voltage Controlled Proportional Driver

C:2: Current Controlled Proportional Driver

The current controlled proportional driver relies on a low-loss transformer in the drain or source path to provide feedback I_D of the GA10JT12-CAL during on-state to supply $I_{G,steady}$ into the device gate. $I_{G,steady}$ will then increase or decrease in response to I_D at a fixed forced current gain which is set be the turns ratio of the transformer, $h_{lorce} = I_D / I_G = N_2 / N_1$. GA10JT12- CAL is initially tuned-on using a gate current pulse supplied into an RC drive circuit to allow I_D current to begin flowing. This topology allows $I_{G,steady}$, and thus the gate drive power consumption, to be reduced while I_D is relatively low or for $I_{G,steady}$ to increase when is I_D higher. A simplified version of this topology is shown in Figure 24, additional information will be available in the future at http://www.genesicsemi.com/commercial-sic/sic-junction-transistors/.

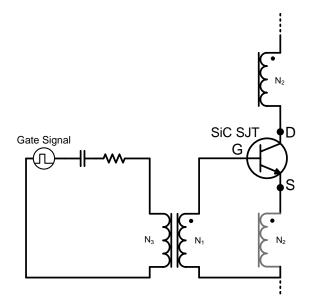
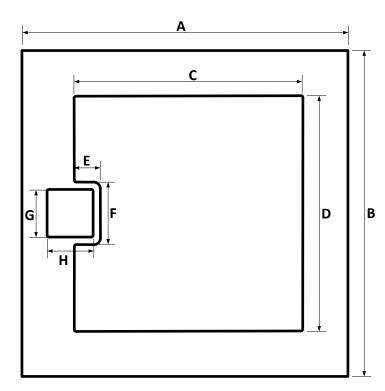


Figure 24: Simplified Current Controlled Proportional Driver

Section VI: Mechanical Parameters

Die Dimensions	2.10 x 2.10	mm ²	83 x 83	mil ²		
Die Area total / active	4.41/3.31	mm ²	6836/5134	mil ²		
Die Thickness	360	μm	14	mil		
Wafer Size	100	mm	3937	mil		
Flat Position	0	deg	0	deg		
Die Frontside Passivation		Polyimide				
Gate/Source Pad Metallization		4000 nm Al				
Bottom Drain Pad Metallization		400 nm Ni + 200 nm Au				
Die Attach	Elect	Electrically conductive glue or solder				
Wire Bond		AI ≤ 10 mil (Source) AI ≤ 3 mil (Gate)				
Reject ink dot size		Φ ≥ 0.3 mm				
	Store in	Store in original container, in dry nitrogen,				
Recommended storage environment	< 6 month	< 6 months at an ambient temperature of 23 °C				

Section VII: Chip Dimensions



		mm	mil
DIE	А	2.10	83
DIE	В	2.10	83
	С	1.47	58
SOURCE	D	1.52	60
WIREBONDABLE	Е	0.17	7
	F	0.40	16
GATE	G	0.30	12
WIREBONDABLE	Н	0.30	12



Revision History					
Date Revision Comments Supersedes					
2016/02/26	2	Updated Electrical Characteristics			
2015/02/05	1	Updated Electrical Characteristics			
2014/07/14	0	Initial release			

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Die Datasheet

Section VIII: SPICE Model Parameters

GeneSiC

SEMICONDUCTOR

This is a secure document. Please copy this code from the SPICE model PDF file on our website (http://www.genesicsemi.com/images/hit_sic/baredie/sjt/GA10JT12-CAL_SPICE.pdf) into LTSPICE (version 4) software for simulation of the GA10JT12-CAL.

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     $Date: 26-FEB-2016
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 OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
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* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
 Models accurate up to 2 times rated drain current.
.model GA10JT12 NPN
+ IS
           9.833E-48
+ ISE
           1.073E-26
+ EG
           3.23
+ BF
           87
+ BR
           0.55
           5000
+ IKF
+ NF
           1
+ NE
           2
+ RB
           4.67
+ IRB
           0.001
+ RBM
           0.16
+ RE
           0.005
+ RC
           0.08
+ CJC
           229.9E-12
+ VJC
           3.22
+ MJC
           0.492
           1244E-9
+ CJE
           2.86
+ VJE
+ MJE
           0.465
+ XTI
           3
           -1.35
+ XTB
           7E-3
+ TRC1
+ VCEO
           1200
+ ICRATING 10
+ MFG
           GeneSiC Semiconductor
* End of GA10JT12 SPICE Model
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